Abstracts

Precise Dielectric Measurements of Low-Loss Materials at Millimeter and Submillimeter Wavelengths

M.N. Afsar and G.W. Chantry. "Precise Dielectric Measurements of Low-Loss Materials at Millimeter and Submillimeter Wavelengths." 1977 Transactions on Microwave Theory and Techniques 25.6 (Jun. 1977 [T-MTT] (Special Issue on the Proceedings of the Second International Conference on Submillimeter Waves and Their Applications)): 509-512.

Transmission dispersive Fourier transform, spectrometry (DFTS) has been used for the measurements of both real and imaginary parts of the complex relative permittivity of low-loss materials at millimeter and submillimeter wavelengths. The materials investigated include cis and trans decalin and polypropylene.

❑ Return to main document.